

J-997 U.S. PRO
10/09/050

03/05/02

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE				Atty. Docket No. DE 010063		Serial No.	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Applicant Michael KAUS et al.			
				Filing Date CONCURRENTLY		Group	

U.S. PATENT DOCUMENTS												
Ex. Int.	AA	AB	AC	AD	AE	AF	Document Number	Date	Name	Class	Sub-class	Filing Date If Approp.

FOREIGN PATENT DOCUMENTS											
AG	AH	AI	AJ	AK	Document Number	Date	Country	Class	Sub-class	Trans.	
										Yes	No

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)		
CK	AL	McInerney et al., "Deformable models in medical image analysis: a survey", Medical Image Analysis, 1 (2), pp. 91 to 108, 1996.
	AM	
	AN	

Examiner: <i>Craig W. [Signature]</i>	Date Considered: <i>2/15/05</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.



Form PTO-1005 U.S. DEPARTMENT OF COMMERCE (REV. 7-80) PATENT AND TRADEMARK OFFICE		Atty. Docket No. DE 010063		Serial No. 10/091,050									
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)		Applicant MICHAEL KAUS ET AL.											
		Filing Date 3/5/02		Group 2183									
U.S. PATENT DOCUMENTS													
Ex. Int.		Document Number							Date	Name	Class	Sub- class	Filing Date If Approp.
CK	AA	6	2	0	1	5	4	3	3/13/01	O'DONNELL ET AL.	345	420	
	AB												
	AC												
	AD												
	AE												
	AF												
FOREIGN PATENT DOCUMENTS													
		Document Number							Date	Country	Class	Sub- class	Trans. Yes No
	AG												
	AH												
	AI												
	AJ												
	AK												
OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)													
	AL												
	AM												
	AN												
Examiner		<i>Craig W. [Signature]</i>								Date Considered 2/15/05			
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